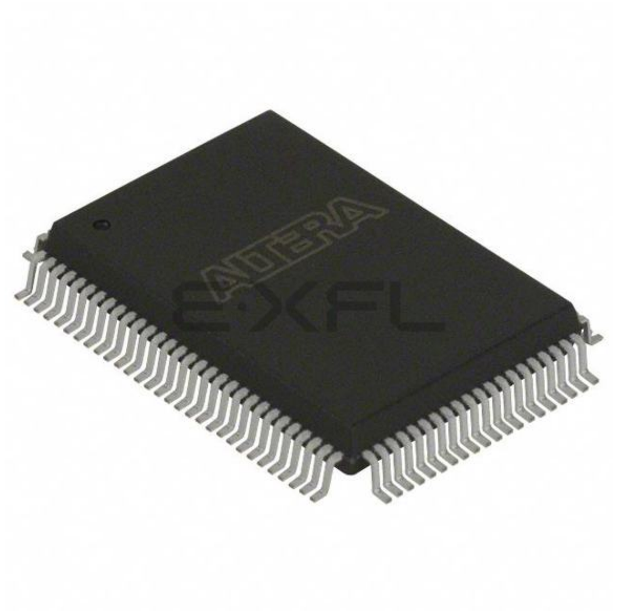


Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	4.5V ~ 5.5V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	84
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7128sqi100-10n

The MAX 7000E devices—including the EPM7128E, EPM7160E, EPM7192E, and EPM7256E devices—have several enhanced features: additional global clocking, additional output enable controls, enhanced interconnect resources, fast input registers, and a programmable slew rate.

In-system programmable MAX 7000 devices—called MAX 7000S devices—include the EPM7032S, EPM7064S, EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices. MAX 7000S devices have the enhanced features of MAX 7000E devices as well as JTAG BST circuitry in devices with 128 or more macrocells, ISP, and an open-drain output option. See Table 4.

Table 4. MAX 7000 Device Features

Feature	EPM7032 EPM7064 EPM7096	All MAX 7000E Devices	All MAX 7000S Devices
ISP via JTAG interface			✓
JTAG BST circuitry			✓*(1)*
Open-drain output option			✓
Fast input registers		✓	✓
Six global output enables		✓	✓
Two global clocks		✓	✓
Slew-rate control		✓	✓
MultiVolt interface *(2)*	✓	✓	✓
Programmable register	✓	✓	✓
Parallel expanders	✓	✓	✓
Shared expanders	✓	✓	✓
Power-saving mode	✓	✓	✓
Security bit	✓	✓	✓
PCI-compliant devices available	✓	✓	✓

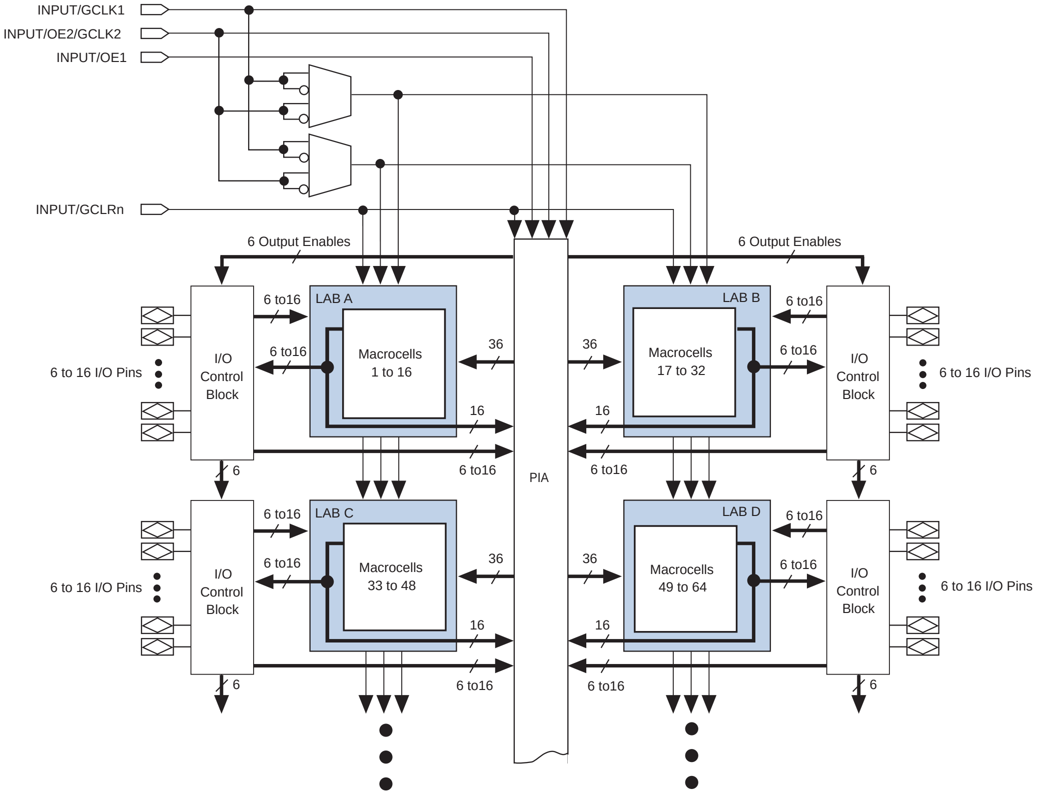
Notes:

(1) Available only in EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices only.

(2) The MultiVolt I/O interface is not available in 44-pin packages.

Figure 2 shows the architecture of MAX 7000E and MAX 7000S devices.

Figure 2. MAX 7000E & MAX 7000S Device Block Diagram



Logic Array Blocks

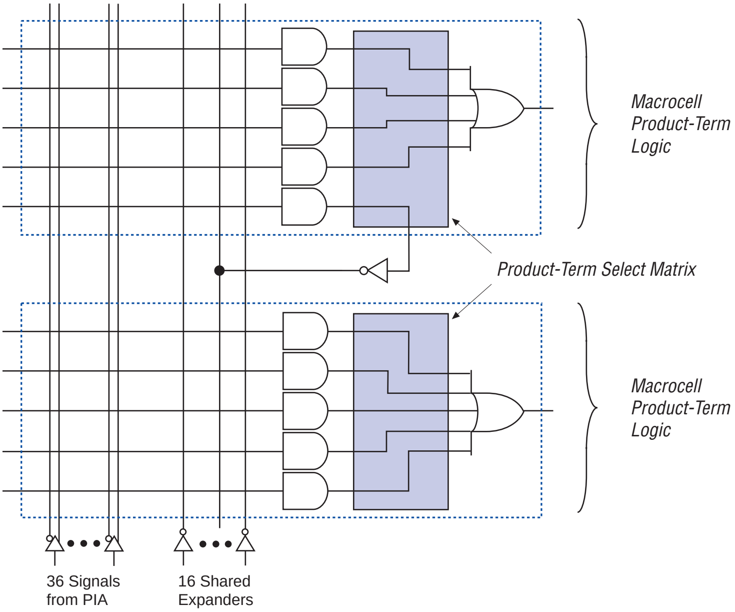
The MAX 7000 device architecture is based on the linking of high-performance, flexible, logic array modules called logic array blocks (LABs). LABs consist of 16-macrocell arrays, as shown in Figures 1 and 2. Multiple LABs are linked together via the programmable interconnect array (PIA), a global bus that is fed by all dedicated inputs, I/O pins, and macrocells.

Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay (t_{SEXP}) is incurred when shareable expanders are used. Figure 5 shows how shareable expanders can feed multiple macrocells.

Figure 5. Shareable Expanders

Shareable expanders can be shared by any or all macrocells in an LAB.

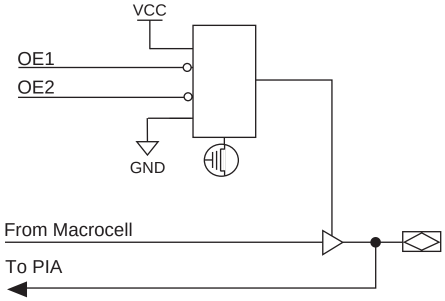


Parallel Expanders

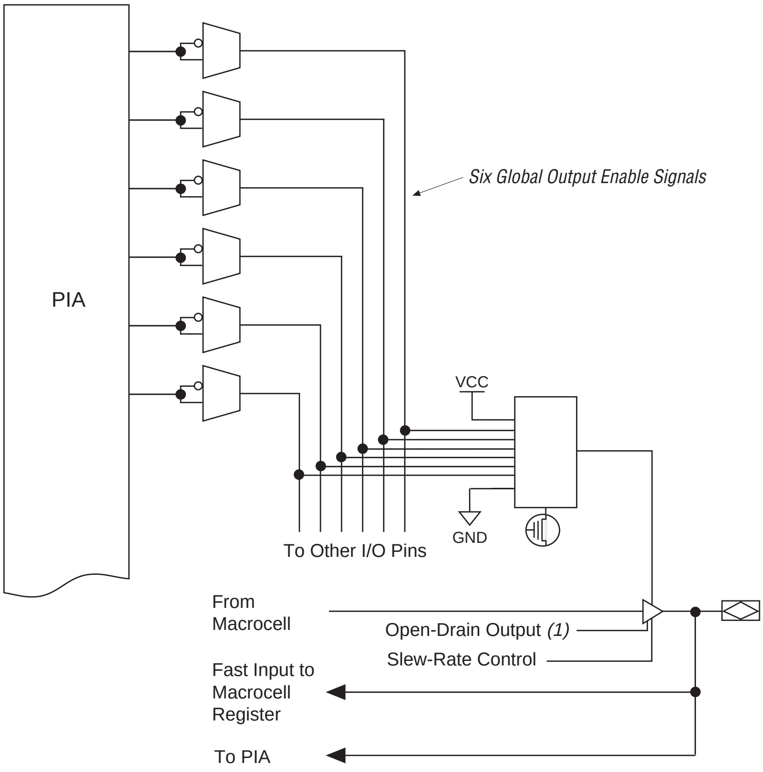
Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell `OR` logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

Figure 8. I/O Control Block of MAX 7000 Devices

EPM7032, EPM7064 & EPM7096 Devices



MAX 7000E & MAX 7000S Devices



Note:

(1) The open-drain output option is available only in MAX 7000S devices.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to V_{CC}, the output is enabled.

The MAX 7000 architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

In-System Programmability (ISP)

MAX 7000S devices are in-system programmable via an industry-standard 4-pin Joint Test Action Group (JTAG) interface (IEEE Std. 1149.1-1990). ISP allows quick, efficient iterations during design development and debugging cycles. The MAX 7000S architecture internally generates the high programming voltage required to program EEPROM cells, allowing in-system programming with only a single 5.0 V power supply. During in-system programming, the I/O pins are tri-stated and pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k¾.

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board with standard in-circuit test equipment before they are programmed. MAX 7000S devices can be programmed by downloading the information via in-circuit testers (ICT), embedded processors, or the Altera MasterBlaster, ByteBlasterMV, ByteBlaster, BitBlaster download cables. (The ByteBlaster cable is obsolete and is replaced by the ByteBlasterMV cable, which can program and configure 2.5-V, 3.3-V, and 5.0-V devices.) Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling and allows devices to be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. Because some in-circuit testers cannot support an adaptive algorithm, Altera offers devices tested with a constant algorithm. Devices tested to the constant algorithm have an “F” suffix in the ordering code.

The Jam™ Standard Test and Programming Language (STAPL) can be used to program MAX 7000S devices with in-circuit testers, PCs, or embedded processor.

Programmable Speed/Power Control

MAX 7000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000 device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, and t_{SEXP}, $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters.

Output Configuration

MAX 7000 device outputs can be programmed to meet a variety of system-level requirements.

MultiVolt I/O Interface

MAX 7000 devices—except 44-pin devices—support the MultiVolt I/O interface feature, which allows MAX 7000 devices to interface with systems that have differing supply voltages. The 5.0-V devices in all packages can be set for 3.3-V or 5.0-V I/O pin operation. These devices have one set of `VCC` pins for internal operation and input buffers (`VCCINT`), and another set for I/O output drivers (`VCCIO`).

The `VCCINT` pins must always be connected to a 5.0-V power supply. With a 5.0-V V_{CCINT} level, input voltage thresholds are at TTL levels, and are therefore compatible with both 3.3-V and 5.0-V inputs.

The `VCCIO` pins can be connected to either a 3.3-V or a 5.0-V power supply, depending on the output requirements. When the `VCCIO` pins are connected to a 5.0-V supply, the output levels are compatible with 5.0-V systems. When V_{CCIO} is connected to a 3.3-V supply, the output high is 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V_{CCIO} levels lower than 4.75 V incur a nominally greater timing delay of t_{OD2} instead of t_{OD1}.

Open-Drain Output Option (MAX 7000S Devices Only)

MAX 7000S devices provide an optional open-drain (functionally equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-`OR` plane.

The instruction register length of MAX 7000S devices is 10 bits. Tables 10 and 11 show the boundary-scan register length and device IDCODE information for MAX 7000S devices.

Table 10. MAX 7000S Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EPM7032S	1 *(1)*
EPM7064S	1 *(1)*
EPM7128S	288
EPM7160S	312
EPM7192S	360
EPM7256S	480

Note:

(1) This device does not support JTAG boundary-scan testing. Selecting either the EXTEST or SAMPLE/PRELOAD instruction will select the one-bit bypass register.

Table 11. 32-Bit MAX 7000 Device IDCODE *Note (1)*

Device	IDCODE (32 Bits)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	1 (1 Bit) *(2)*
EPM7032S	`0000`	`0111 0000 0011 0010`	`00001101110`	`1`
EPM7064S	`0000`	`0111 0000 0110 0100`	`00001101110`	`1`
EPM7128S	`0000`	`0111 0001 0010 1000`	`00001101110`	`1`
EPM7160S	`0000`	`0111 0001 0110 0000`	`00001101110`	`1`
EPM7192S	`0000`	`0111 0001 1001 0010`	`00001101110`	`1`
EPM7256S	`0000`	`0111 0010 0101 0110`	`00001101110`	`1`

Notes:

(1) The most significant bit (MSB) is on the left.

(2) The least significant bit (LSB) for all JTAG IDCODEs is `1`.

Figure 9 shows the timing requirements for the JTAG signals.

Figure 9. MAX 7000 JTAG Waveforms

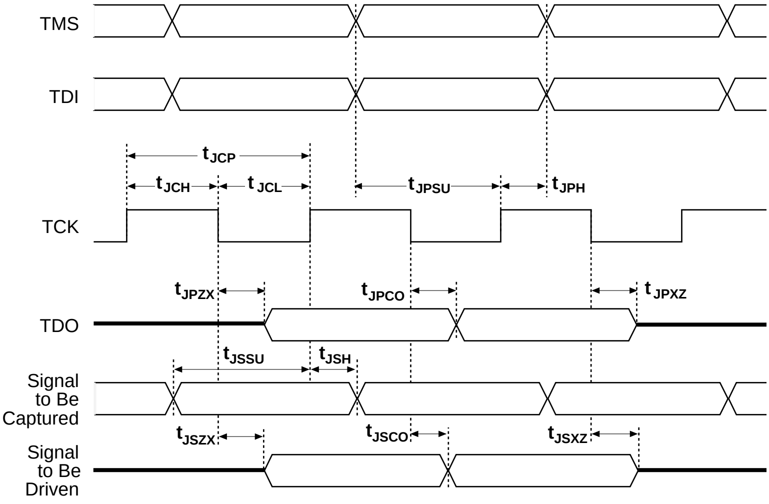


Table 12 shows the JTAG timing parameters and values for MAX 7000S devices.

Table 12. JTAG Timing Parameters & Values for MAX 7000S Devices

Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		25	ns
t_{JSZX}	Update register high impedance to valid output		25	ns
t_{JSXZ}	Update register valid output to high impedance		25	ns

For more information, see *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)*.

Design Security

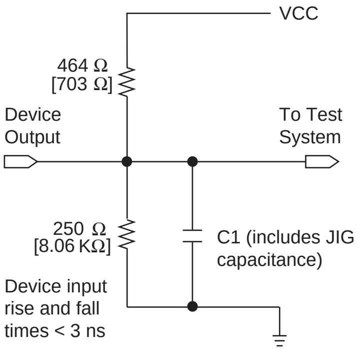
All MAX 7000 devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

Generic Testing

Each MAX 7000 device is functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in Figure 10. Test patterns can be used and then erased during early stages of the production flow.

Figure 10. MAX 7000 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V devices and outputs. Numbers without brackets are for 3.3-V devices and outputs.



QFP Carrier & Development Socket

MAX 7000 and MAX 7000E devices in QFP packages with 100 or more pins are shipped in special plastic carriers to protect the QFP leads. The carrier is used with a prototype development socket and special programming hardware available from Altera. This carrier technology makes it possible to program, test, erase, and reprogram a device without exposing the leads to mechanical stress.

For detailed information and carrier dimensions, refer to the *QFP Carrier & Development Socket Data Sheet*.

MAX 7000S devices are not shipped in carriers.

Table 20. MAX 7000 & MAX 7000E Internal Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade -6		Speed Grade -7		Unit
			Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			0.4		0.5	ns
t_{IO}	I/O input pad and buffer delay			0.4		0.5	ns
t_{FIN}	Fast input delay	*(2)*		0.8		1.0	ns
t_{SEXP}	Shared expander delay			3.5		4.0	ns
t_{PEXP}	Parallel expander delay			0.8		0.8	ns
t_{LAD}	Logic array delay			2.0		3.0	ns
t_{LAC}	Logic control array delay			2.0		3.0	ns
t_{IOE}	Internal output enable delay	*(2)*				2.0	ns
t_{OD1}	Output buffer and pad delay Slow slew rate = off, V_{CCIO} = 5.0 V	C1 = 35 pF		2.0		2.0	ns
t_{OD2}	Output buffer and pad delay Slow slew rate = off, V_{CCIO} = 3.3 V	C1 = 35 pF *(7)*		2.5		2.5	ns
t_{OD3}	Output buffer and pad delay Slow slew rate = on, V_{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF *(2)*		7.0		7.0	ns
t_{ZX1}	Output buffer enable delay Slow slew rate = off, V_{CCIO} = 5.0 V	C1 = 35 pF		4.0		4.0	ns
t_{ZX2}	Output buffer enable delay Slow slew rate = off, V_{CCIO} = 3.3 V	C1 = 35 pF *(7)*		4.5		4.5	ns
t_{ZX3}	Output buffer enable delay Slow slew rate = on V_{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF *(2)*		9.0		9.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0	ns
t_{SU}	Register setup time		3.0		3.0		ns
t_{H}	Register hold time		1.5		2.0		ns
t_{FSU}	Register setup time of fast input	*(2)*	2.5		3.0		ns
t_{FH}	Register hold time of fast input	*(2)*	0.5		0.5		ns
t_{RD}	Register delay			0.8		1.0	ns
t_{COMB}	Combinatorial delay			0.8		1.0	ns
t_{IC}	Array clock delay			2.5		3.0	ns
t_{EN}	Register enable time			2.0		3.0	ns
t_{GLOB}	Global control delay			0.8		1.0	ns
t_{PRE}	Register preset time			2.0		2.0	ns
t_{CLR}	Register clear time			2.0		2.0	ns
t_{PIA}	PIA delay			0.8		1.0	ns
t_{LPA}	Low-power adder	*(8)*		10.0		10.0	ns

Table 21. MAX 7000 & MAX 7000E External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			MAX 7000E (-10P)		MAX 7000 (-10) MAX 7000E (-10)		
			Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t_{SU}	Global clock setup time		7.0		8.0		ns
t_{H}	Global clock hold time		0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input	*(2)*	3.0		3.0		ns
t_{FH}	Global clock hold time of fast input	*(2)*	0.5		0.5		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF		5.0		5	ns
t_{CH}	Global clock high time		4.0		4.0		ns
t_{CL}	Global clock low time		4.0		4.0		ns
t_{ASU}	Array clock setup time		2.0		3.0		ns
t_{AH}	Array clock hold time		3.0		3.0		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF		10.0		10.0	ns
t_{ACH}	Array clock high time		4.0		4.0		ns
t_{ACL}	Array clock low time		4.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	4.0		4.0		ns
t_{ODH}	Output data hold time after clock	C1 = 35 pF *(4)*	1.0		1.0		ns
t_{CNT}	Minimum global clock period			10.0		10.0	ns
f_{CNT}	Maximum internal global clock frequency	*(5)*	100.0		100.0		MHz
t_{ACNT}	Minimum array clock period			10.0		10.0	ns
f_{ACNT}	Maximum internal array clock frequency	*(5)*	100.0		100.0		MHz
f_{MAX}	Maximum clock frequency	*(6)*	125.0		125.0		MHz

Table 23. MAX 7000 & MAX 7000E External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade				Unit
			MAX 7000E (-12P)		MAX 7000 (-12) MAX 7000E (-12)		
			Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t_{SU}	Global clock setup time		7.0		10.0		ns
t_{H}	Global clock hold time		0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input	*(2)*	3.0		3.0		ns
t_{FH}	Global clock hold time of fast input	*(2)*	0.0		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF		6.0		6.0	ns
t_{CH}	Global clock high time		4.0		4.0		ns
t_{CL}	Global clock low time		4.0		4.0		ns
t_{ASU}	Array clock setup time		3.0		4.0		ns
t_{AH}	Array clock hold time		4.0		4.0		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF		12.0		12.0	ns
t_{ACH}	Array clock high time		5.0		5.0		ns
t_{ACL}	Array clock low time		5.0		5.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(3)*	5.0		5.0		ns
t_{ODH}	Output data hold time after clock	C1 = 35 pF *(4)*	1.0		1.0		ns
t_{CNT}	Minimum global clock period			11.0		11.0	ns
f_{CNT}	Maximum internal global clock frequency	*(5)*	90.9		90.9		MHz
t_{ACNT}	Minimum array clock period			11.0		11.0	ns
f_{ACNT}	Maximum internal array clock frequency	*(5)*	90.9		90.9		MHz
f_{MAX}	Maximum clock frequency	*(6)*	125.0		125.0		MHz

Table 26. MAX 7000 & MAX 7000E Internal Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-15		-15T		-20		
			Min	Max	Min	Max	Min	Max	
t_{IN}	Input pad and buffer delay			2.0		2.0		3.0	ns
t_{IO}	I/O input pad and buffer delay			2.0		2.0		3.0	ns
t_{FIN}	Fast input delay	*(2)*		2.0		–		4.0	ns
t_{SEXP}	Shared expander delay			8.0		10.0		9.0	ns
t_{PEXP}	Parallel expander delay			1.0		1.0		2.0	ns
t_{LAD}	Logic array delay			6.0		6.0		8.0	ns
t_{LAC}	Logic control array delay			6.0		6.0		8.0	ns
t_{IOE}	Internal output enable delay	*(2)*		3.0		–		4.0	ns
t_{OD1}	Output buffer and pad delay Slow slew rate = off V_{CCIO} = 5.0 V	C1 = 35 pF		4.0		4.0		5.0	ns
t_{OD2}	Output buffer and pad delay Slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF *(7)*		5.0		–		6.0	ns
t_{OD3}	Output buffer and pad delay Slow slew rate = on V_{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF *(2)*		8.0		–		9.0	ns
t_{ZX1}	Output buffer enable delay Slow slew rate = off V_{CCIO} = 5.0 V	C1 = 35 pF		6.0		6.0		10.0	ns
t_{ZX2}	Output buffer enable delay Slow slew rate = off V_{CCIO} = 3.3 V	C1 = 35 pF *(7)*		7.0		–		11.0	ns
t_{ZX3}	Output buffer enable delay Slow slew rate = on V_{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF *(2)*		10.0		–		14.0	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		6.0		6.0		10.0	ns
t_{SU}	Register setup time		4.0		4.0		4.0		ns
t_{H}	Register hold time		4.0		4.0		5.0		ns
t_{FSU}	Register setup time of fast input	*(2)*	2.0		–		4.0		ns
t_{FH}	Register hold time of fast input	*(2)*	2.0		–		3.0		ns
t_{RD}	Register delay			1.0		1.0		1.0	ns
t_{COMB}	Combinatorial delay			1.0		1.0		1.0	ns
t_{IC}	Array clock delay			6.0		6.0		8.0	ns
t_{EN}	Register enable time			6.0		6.0		8.0	ns
t_{GLOB}	Global control delay			1.0		1.0		3.0	ns
t_{PRE}	Register preset time			4.0		4.0		4.0	ns
t_{CLR}	Register clear time			4.0		4.0		4.0	ns
t_{PIA}	PIA delay			2.0		2.0		3.0	ns
t_{LPA}	Low-power adder	*(8)*		13.0		15.0		15.0	ns

Notes to tables:

1. (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
2. (2) This parameter applies to MAX 7000E devices only.
3. (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
4. (4) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
5. (5) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
6. (6) The f_{MAX} values represent the highest frequency for pipelined data.
7. (7) Operating conditions: V_{CCIO} = 3.3 V ± 10% for commercial and industrial use.
8. (8) The t_{LPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, t_{SEXP}, t_{ACL}, and t_{CPPW} parameters for macrocells running in the low-power mode.

Tables 27 and 28 show the EPM7032S AC operating conditions.

Table 27. EPM7032S External Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t_{SU}	Global clock setup time		2.9		4.0		5.0		7.0		ns
t_{H}	Global clock hold time		0.0		0.0		0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input		2.5		2.5		2.5		3.0		ns
t_{FH}	Global clock hold time of fast input		0.0		0.0		0.0		0.5		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF		3.2		3.5		4.3		5.0	ns
t_{CH}	Global clock high time		2.0		2.5		3.0		4.0		ns
t_{CL}	Global clock low time		2.0		2.5		3.0		4.0		ns
t_{ASU}	Array clock setup time		0.7		0.9		1.1		2.0		ns
t_{AH}	Array clock hold time		1.8		2.1		2.7		3.0		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF		5.4		6.6		8.2		10.0	ns
t_{ACH}	Array clock high time		2.5		2.5		3.0		4.0		ns
t_{ACL}	Array clock low time		2.5		2.5		3.0		4.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(2)*	2.5		2.5		3.0		4.0		ns
t_{ODH}	Output data hold time after clock	C1 = 35 pF *(3)*	1.0		1.0		1.0		1.0		ns
t_{CNT}	Minimum global clock period			5.7		7.0		8.6		10.0	ns
f_{CNT}	Maximum internal global clock frequency	*(4)*	175.4		142.9		116.3		100.0		MHz
t_{ACNT}	Minimum array clock period			5.7		7.0		8.6		10.0	ns

Notes to tables:

(1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
(2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
(3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
(4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
(5) The f_{MAX} values represent the highest frequency for pipelined data.
(6) Operating conditions: V_{CCIO} = 3.3 V ± 10% for commercial and industrial use.
(7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
(8) The t_{LPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, t_{SEXP}, t_{ACL}, and t_{CPPW} parameters for macrocells running in the low-power mode.

Tables 33 and 34 show the EPM7160S AC operating conditions.

Table 33. EPM7160S External Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
t_{PD1}	Input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t_{PD2}	I/O input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns
t_{SU}	Global clock setup time		3.4		4.2		7.0		11.0		ns
t_H	Global clock hold time		0.0		0.0		0.0		0.0		ns
t_{FSU}	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t_{FH}	Global clock hold time of fast input		0.0		0.0		0.5		0.0		ns
t_{CO1}	Global clock to output delay	C1 = 35 pF		3.9		4.8		5		8	ns
t_{CH}	Global clock high time		3.0		3.0		4.0		5.0		ns
t_{CL}	Global clock low time		3.0		3.0		4.0		5.0		ns
t_{ASU}	Array clock setup time		0.9		1.1		2.0		4.0		ns
t_{AH}	Array clock hold time		1.7		2.1		3.0		4.0		ns
t_{ACO1}	Array clock to output delay	C1 = 35 pF		6.4		7.9		10.0		15.0	ns
t_{ACH}	Array clock high time		3.0		3.0		4.0		6.0		ns
t_{ACL}	Array clock low time		3.0		3.0		4.0		6.0		ns
t_{CPPW}	Minimum pulse width for clear and preset	*(2)*	2.5		3.0		4.0		6.0		ns
t_{ODH}	Output data hold time after clock	C1 = 35 pF *(3)*	1.0		1.0		1.0		1.0		ns
t_{CNT}	Minimum global clock period			6.7		8.2		10.0		13.0	ns
f_{CNT}	Maximum internal global clock frequency	*(4)*	149.3		122.0		100.0		76.9		MHz

Table 34. EPM7160S Internal Timing Parameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
t_{CLR}	Register clear time			2.4		3.0		3.0		4.0	ns
t_{PIA}	PIA delay	*(7)*		1.6		2.0		1.0		2.0	ns
t_{LPA}	Low-power adder	*(8)*		11.0		10.0		11.0		13.0	ns

Notes to tables:

(1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.

(2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.

(3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.

(4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.

(5) The $\mathbf{f_{MAX}}$ values represent the highest frequency for pipelined data.

(6) Operating conditions: V_{CCIO} = 3.3 V ± 10% for commercial and industrial use.

(7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.

(8) The t_{LPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, t_{SEXP}, $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters for macrocells running in the low-power mode.

Tables 35 and 36 show the EPM7192S AC operating conditions.

Table 35. EPM7192S External Timing Parameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
$\mathbf{t_{PD1}}$	Input to non-registered output	C1 = 35 pF		7.5		10.0		15.0	ns
$\mathbf{t_{PD2}}$	I/O input to non-registered output	C1 = 35 pF		7.5		10.0		15.0	ns
$\mathbf{t_{SU}}$	Global clock setup time		4.1		7.0		11.0		ns
$\mathbf{t_{H}}$	Global clock hold time		0.0		0.0		0.0		ns
$\mathbf{t_{FSU}}$	Global clock setup time of fast input		3.0		3.0		3.0		ns
$\mathbf{t_{FH}}$	Global clock hold time of fast input		0.0		0.5		0.0		ns
$\mathbf{t_{CO1}}$	Global clock to output delay	C1 = 35 pF		4.7		5.0		8.0	ns
$\mathbf{t_{CH}}$	Global clock high time		3.0		4.0		5.0		ns
$\mathbf{t_{CL}}$	Global clock low time		3.0		4.0		5.0		ns
$\mathbf{t_{ASU}}$	Array clock setup time		1.0		2.0		4.0		ns

Notes to tables:

(1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.

(2) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.

(3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.

(4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.

(5) The $\mathbf{f_{MAX}}$ values represent the highest frequency for pipelined data.

(6) Operating conditions: V_{CCIO} = 3.3 V ± 10% for commercial and industrial use.

(7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.

(8) The t_{LPA} parameter must be added to the t_{LAD}, t_{LAC}, t_{IC}, t_{EN}, t_{SEXP}, $\mathbf{t_{ACL}}$, and $\mathbf{t_{CPPW}}$ parameters for macrocells running in the low-power mode.

Power Consumption

Supply power (P) versus frequency ($\mathbf{f_{MAX}}$ in MHz) for MAX 7000 devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The P_{IO} value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*.

The I_{CCINT} value, which depends on the switching frequency and the application logic, is calculated with the following equation:

$$I_{CCINT} =$$

$$A \times MC_{TON} + B \times (MC_{DEV} - MC_{TON}) + C \times MC_{USED} \times \mathbf{f_{MAX}} \times \mathbf{tog_{LC}}$$

The parameters in this equation are shown below:

MC_{TON} = Number of macrocells with the Turbo Bit option turned on, as reported in the MAX+PLUS II Report File (**.rpt**)

MC_{DEV} = Number of macrocells in the device

MC_{USED} = Total number of macrocells in the design, as reported in the MAX+PLUS II Report File (**.rpt**)

$\mathbf{f_{MAX}}$ = Highest clock frequency to the device

$\mathbf{tog_{LC}}$ = Average ratio of logic cells toggling at each clock (typically 0.125)

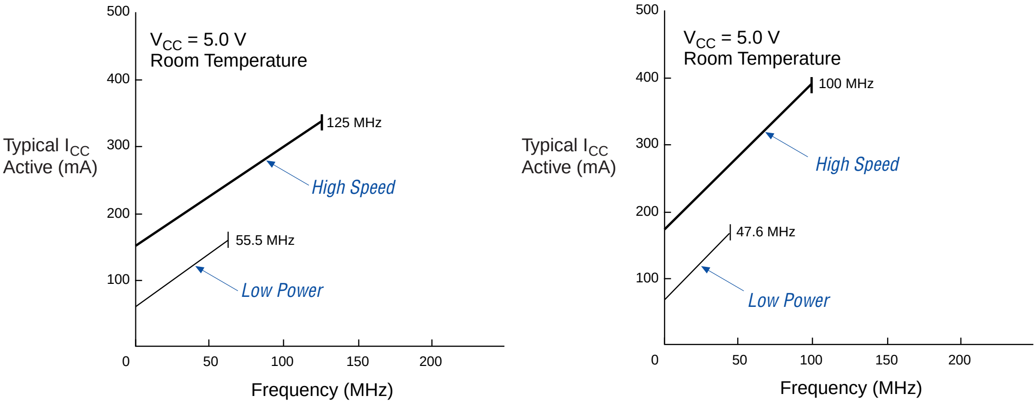
A, B, C = Constants, shown in Table 39

Table 39. MAX 7000 I_{CC} Equation Constants

Device	A	B	C
EPM7032	1.87	0.52	0.144
EPM7064	1.63	0.74	0.144
EPM7096	1.63	0.74	0.144
EPM7128E	1.17	0.54	0.096
EPM7160E	1.17	0.54	0.096
EPM7192E	1.17	0.54	0.096
EPM7256E	1.17	0.54	0.096
EPM7032S	0.93	0.40	0.040
EPM7064S	0.93	0.40	0.040
EPM7128S	0.93	0.40	0.040
EPM7160S	0.93	0.40	0.040
EPM7192S	0.93	0.40	0.040
EPM7256S	0.93	0.40	0.040

This calculation provides an I_{CC} estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual I_{CC} values should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

Figure 14. I_{CC} vs. Frequency for MAX 7000 Devices (Part 2 of 2)

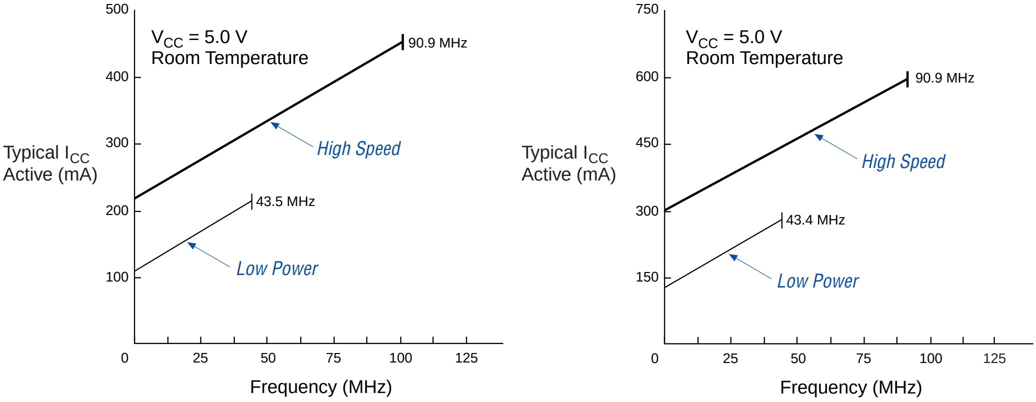


EPM7128E

EPM7160E

EPM7192E

EPM7256E



101 Innovation Drive
San Jose, CA 95134
(408) 544-7000
www.altera.com
Applications Hotline:
(800) 800-EPLD
Literature Services:
literature@altera.com